PHB108NQ03LT

N-channel TrenchMOS logic level FET

Rev. 04 — 2 February 2009 Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Simple gate drive required due to low gate charge
- Suitable for logic level gate drive sources

1.3 Applications

- DC-to-DC convertors
- Switched-mode power supplies

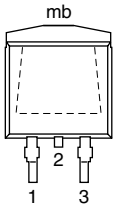
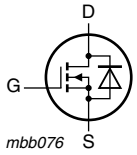
1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C	-	-	25	V
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 5 V; see Figure 1; see Figure 3	-	-	75	A
P_{tot}	total power dissipation	T_{mb} = 25 °C; see Figure 2	-	-	187	W
Dynamic characteristics						
Q_{GD}	gate-drain charge	V_{GS} = 4.5 V; I_D = 25 A; V_{DS} = 12 V; T_j = 25 °C; see Figure 12; see Figure 13	-	5.6	-	nC
Static characteristics						
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see Figure 10; see Figure 11	-	5.3	6	mΩ

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	 SOT404 (D2PAK)	
2	D	drain [1]		
3	S	source		
mb	D	mounting base; connected to drain		

[1] It is not possible to make a connection to pin 2

3. Ordering information

Table 3. Ordering information

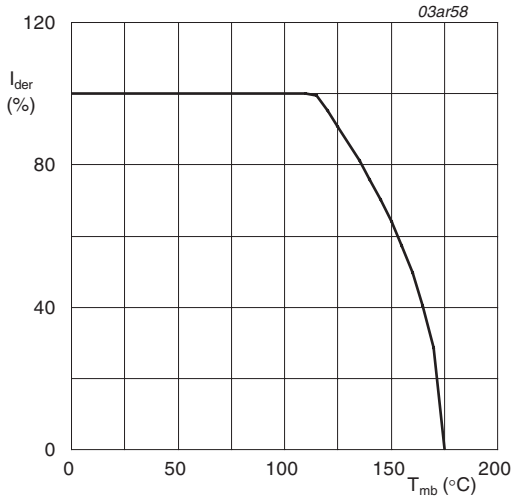
Type number	Package		
	Name	Description	Version
PHB108NQ03LT	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

4. Limiting values

Table 4. Limiting values

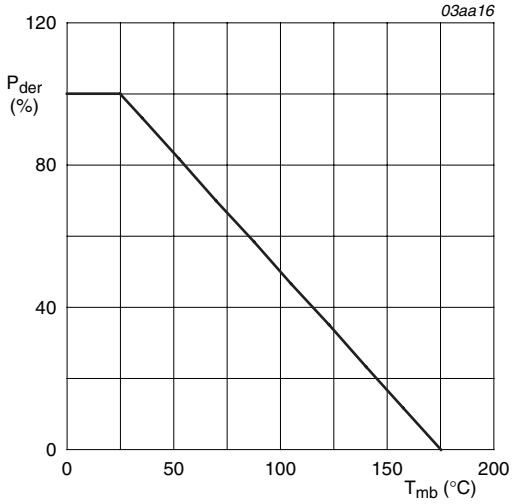
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C	-	25	V
V_{DGR}	drain-gate voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C; $R_{GS} = 20$ kΩ	-	25	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$V_{GS} = 5$ V; $T_{mb} = 25$ °C; see Figure 1; see Figure 3	-	75	A
		$V_{GS} = 5$ V; $T_{mb} = 100$ °C; see Figure 1	-	75	A
I_{DM}	peak drain current	$t_p \leq 10$ µs; pulsed; $T_{mb} = 25$ °C; see Figure 3	-	240	A
P_{tot}	total power dissipation	$T_{mb} = 25$ °C; see Figure 2	-	187	W
T_{stg}	storage temperature		-55	175	°C
T_j	junction temperature		-55	175	°C
Source-drain diode					
I_S	source current	$T_{mb} = 25$ °C	-	75	A
I_{SM}	peak source current	$t_p \leq 10$ µs; pulsed; $T_{mb} = 25$ °C	-	240	A
Avalance ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$V_{GS} = 10$ V; $T_{j(init)} = 25$ °C; $I_D = 43$ A; $V_{sup} \leq 25$ V; unclamped; $t_p = 0.25$ ms; $R_{GS} = 50$ Ω	-	180	mJ



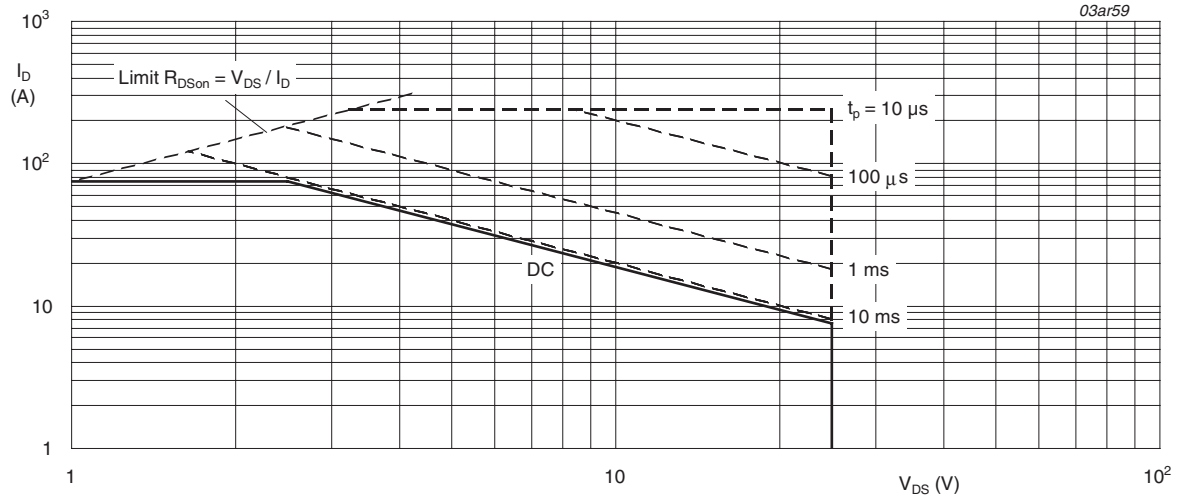
$$I_{der} = \frac{I_D}{I_{D(25°C)}} \times 100\,\%$$

Fig 1. Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25°C)}} \times 100\,\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



$$T_{mb} = 25°C; I_{DM} \text{ is single pulse}; V_{GS} = 5V$$

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air; mounted on a printed-circuit board; minimum footprint	-	50	-	K/W
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.8	K/W

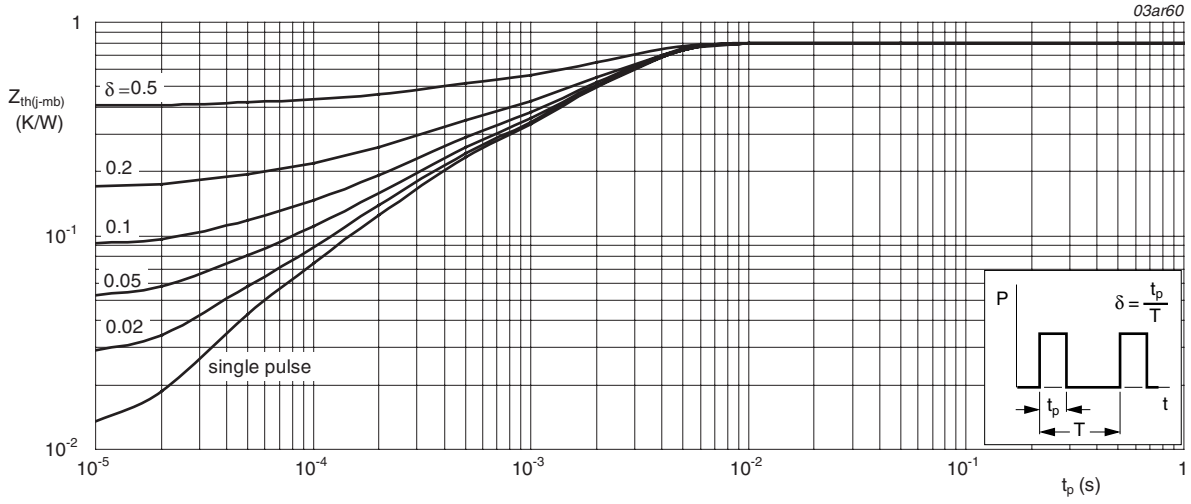


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

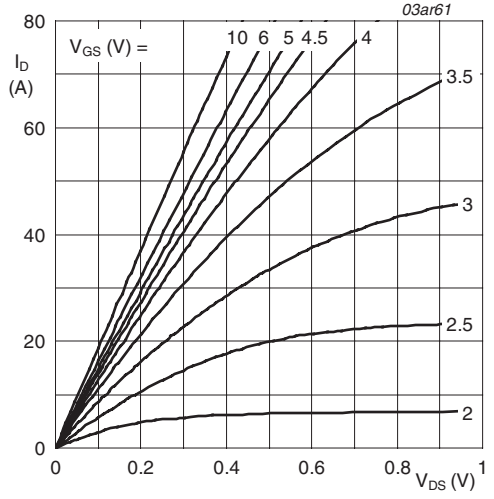
6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C	22	-	-	V
		I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C	25	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS}; T_j = 175 °C; see Figure 8; see Figure 9	0.5	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = -55 °C; see Figure 8; see Figure 9	-	-	2.2	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = 25 °C; see Figure 8; see Figure 9	1	1.5	2	V
I_{DSS}	drain leakage current	V_{DS} = 25 V; V_{GS} = 0 V; T_j = 175 °C	-	-	500	µA
		V_{DS} = 25 V; V_{GS} = 0 V; T_j = 25 °C	-	-	1	µA
I_{GSS}	gate leakage current	V_{GS} = 10 V; V_{DS} = 0 V; T_j = 25 °C	-	0.02	100	nA
		V_{GS} = -10 V; V_{DS} = 0 V; T_j = 25 °C	-	0.02	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 5 V; I_D = 25 A; T_j = 175 °C; see Figure 10; see Figure 11	-	12.1	13.5	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see Figure 10; see Figure 11	-	5.3	6	mΩ
		V_{GS} = 5 V; I_D = 25 A; T_j = 25 °C; see Figure 10; see Figure 11	-	6.7	7.5	mΩ
R_G	internal gate resistance (AC)	f = 1 MHz; T_j = 25 °C	-	1.2	-	Ω
Dynamic characteristics						
$Q_{G(tot)}$	total gate charge	I_D = 25 A; V_{DS} = 12 V; V_{GS} = 4.5 V; T_j = 25 °C; see Figure 12; see Figure 13	-	16.3	-	nC
		I_D = 0 A; V_{DS} = 0 V; V_{GS} = 4.5 V; T_j = 25 °C	-	12.5	-	nC
Q_{GS}	gate-source charge	I_D = 25 A; V_{DS} = 12 V; V_{GS} = 4.5 V; T_j = 25 °C; see Figure 12; see Figure 13	-	4	-	nC
Q_{GS1}	pre-threshold gate-source charge		-	2.5	-	nC
Q_{GS2}	post-threshold gate-source charge		-	1.5	-	nC
Q_{GD}	gate-drain charge		-	5.6	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	I_D = 25 A; V_{DS} = 12 V; T_j = 25 °C; see Figure 12; see Figure 13	-	2.4	-	V
C_{iss}	input capacitance	V_{DS} = 12 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C; see Figure 14	-	1375	-	pF
		V_{DS} = 0 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C	-	2120	-	pF
C_{oss}	output capacitance	V_{DS} = 12 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C; see Figure 14	-	640	-	pF
C_{rss}	reverse transfer capacitance		-	250	-	pF

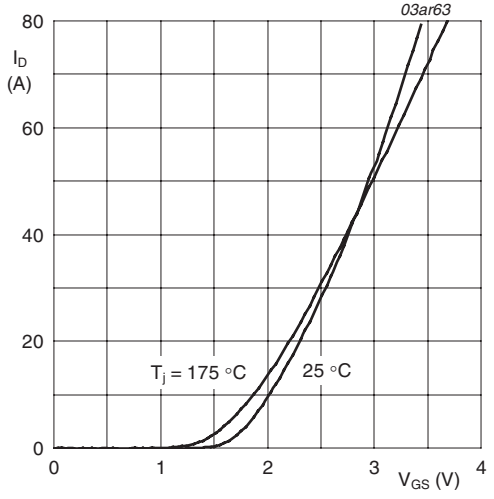
Table 6. Characteristics *…continued*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{d(on)}$	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω; V_{GS} = 4.5 V; $R_{G(ext)}$ = 5.6 Ω; T_j = 25 °C	-	15	-	ns
t_r	rise time		-	38	-	ns
$t_{d(off)}$	turn-off delay time		-	32	-	ns
t_f	fall time		-	25	-	ns
Source-drain diode						
V_{SD}	source-drain voltage	I_S = 25 A; V_{GS} = 0 V; T_j = 25 °C; see Figure 15	-	0.86	1.2	V
t_{rr}	reverse recovery time	I_S = 20 A; dI_S/dt = -100 A/µs; V_{GS} = 0 V; V_{DS} = 25 V; T_j = 25 °C	-	34	-	ns
Q_r	recovered charge		-	21	-	nC



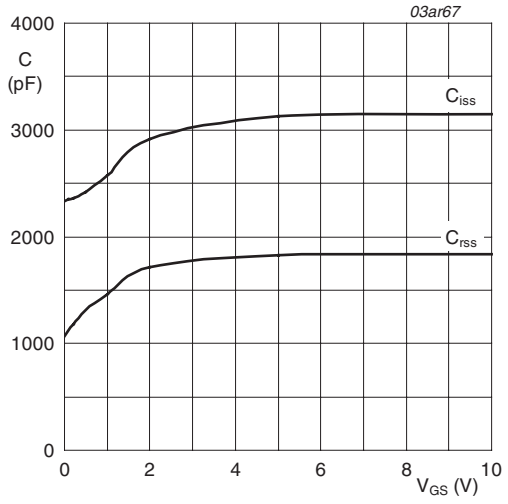
$T_j = 25°C$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



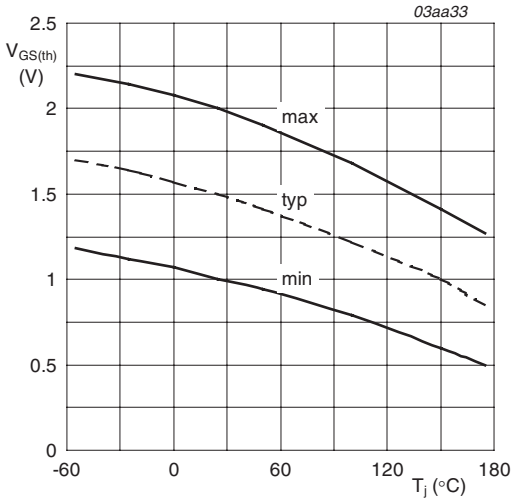
$T_j = 25°C \text{ and } 175°C; V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



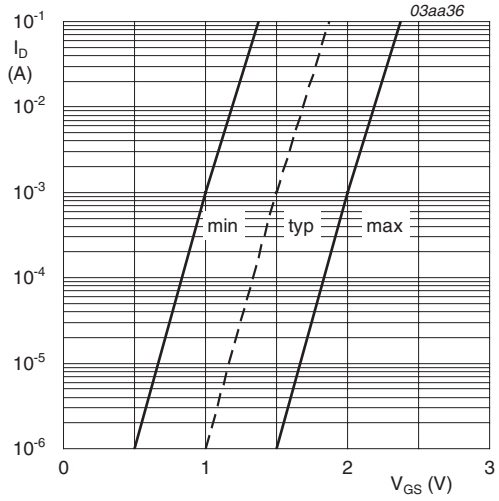
$V_{DS} = 0V$

Fig 7. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



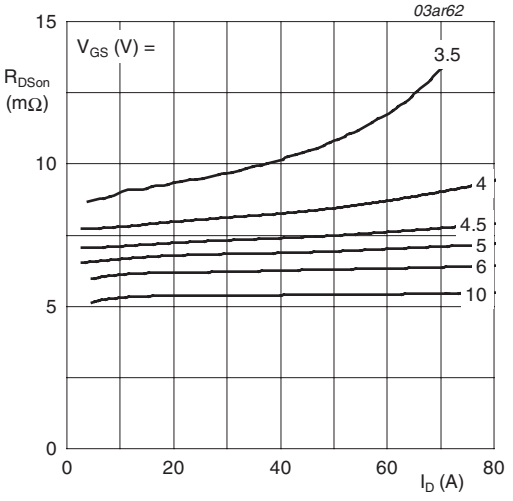
$I_D = 1mA; V_{DS} = V_{GS}$

Fig 8. Gate-source threshold voltage as a function of junction temperature



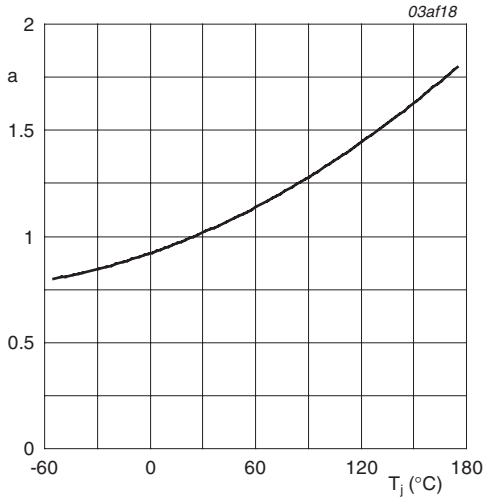
$T_j = 25\,°C; V_{DS} = V_{GS}$

Fig 9. Sub-threshold drain current as a function of gate-source voltage



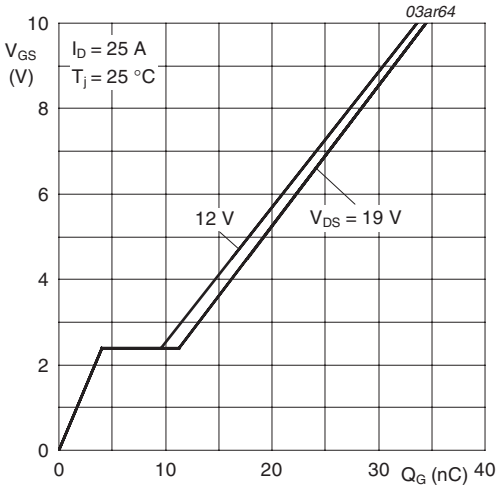
$T_j = 25°C$

Fig 10. Drain-source on-state resistance as a function of drain current; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25°C)}}$$

Fig 11. Normalized drain-source on-state resistance factor as a function of junction temperature



$$I_D = 25A; V_{DS} = 12V \text{ and } 19V$$

Fig 12. Gate-source voltage as a function of gate charge; typical values

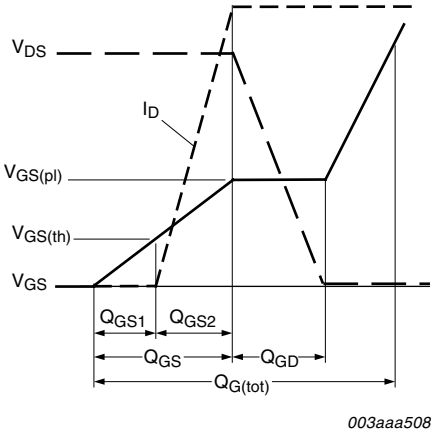
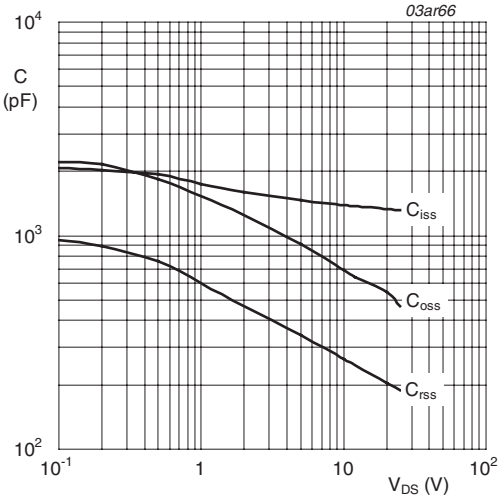
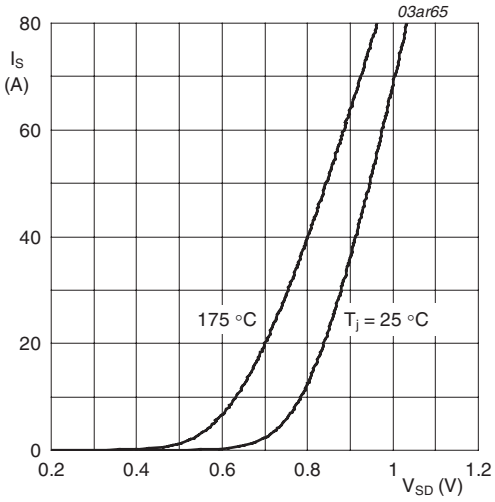


Fig 13. Gate charge waveform definitions



$$V_{GS} = 0V; f = 1MHz$$

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

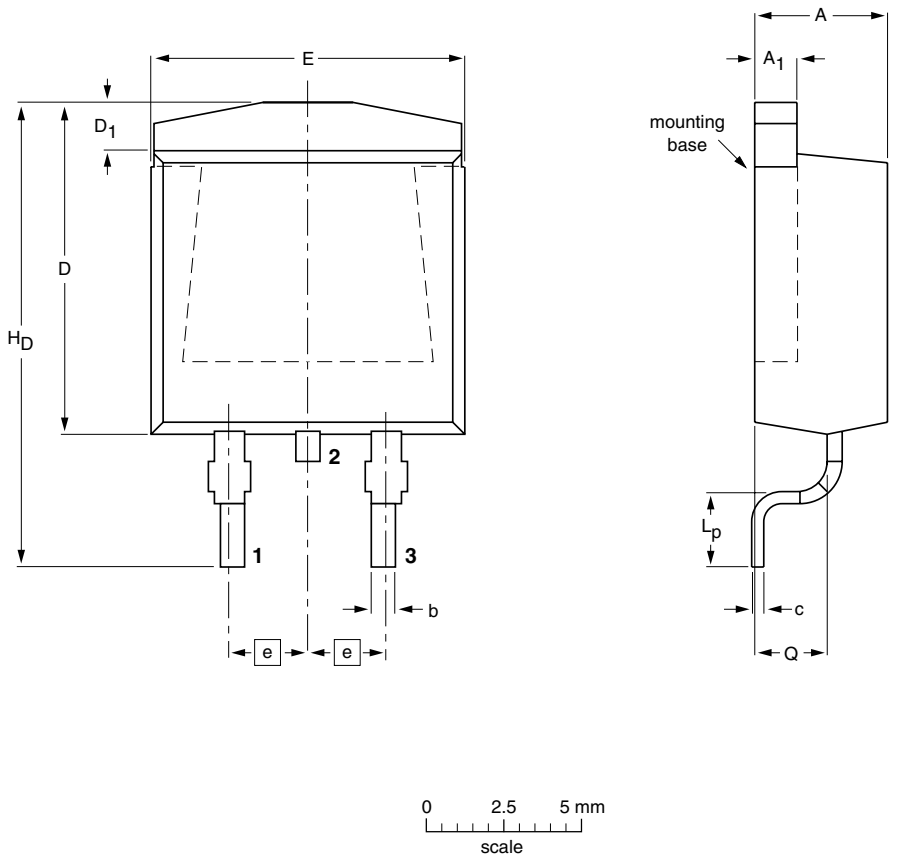


$T_j = 25°C \text{ and } 175°C; V_{GS} = 0V$

Fig 15. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped) **SOT404**



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1	b	c	D max.	D_1	E	e	L_p	H_D	Q
mm	4.50 4.10	1.40 1.27	0.85 0.60	0.64 0.46	11	1.60 1.20	10.30 9.70	2.54	2.90 2.10	15.80 14.80	2.60 2.20

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT404						~~05-02-11~~ 06-03-16

Fig 16. Package outline SOT404 (D2PAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHB108NQ03LT_4	20090202	Product data sheet	-	PHB_PHD_PHU108NQ03LT_3
Modifications:	• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Legal texts have been adapted to the new company name where appropriate.			
PHB_PHD_PHU108NQ03LT_3 (9397 750 14707)	20050418	Product data sheet	2004070095	PHP_PHB_PHD108NQ03LT-02
PHP_PHB_PHD108NQ03LT-02 (9397 750 10159)	20020911	Product data	-	PHP_PHB_PHD108NQ03LT-01
PHP_PHB_PHD108NQ03LT-01 (9397 750 09065)	20011218	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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11. Contents

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